

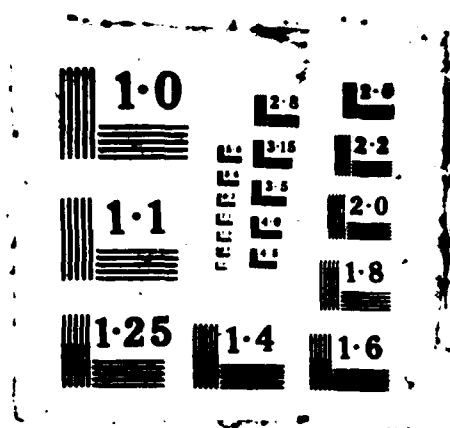
THE PLASMON DISPERSION RELATION ON A ROUGH SURFACE: A  
SIMPLE APPROXIMATION. (U) STATE UNIV OF NEW YORK AT  
BUFFALO DEPT OF CHEMISTRY D A JELSKI ET AL. MAR 87  
UBUFFALO/DC/87/TR-31 N00014-86-K-0043 F/G 28/9

**UNCLASSIFIED**

**F/G 20/9**

NL

[illegible]



AD-A178 167

12

OFFICE OF NAVAL RESEARCH

Contract N00014-K-0043

R & T Code 413f0001---01

TECHNICAL REPORT No. 31

The Plasmon Dispersion Relation on a Rough Surface: A Simple Approximation

by

Daniel Jelski and Thomas F. George

Prepared for Publication

in

Journal of Physical Chemistry

Departments of Chemistry and Physics  
State University of New York at Buffalo  
Buffalo, New York 14260

March 1987

Reproduction in whole or in part is permitted for any purpose of  
the United States Government.

This document has been approved for public release and sale;  
its distribution is unlimited.

DTIC  
ELECTE  
MAR 24 1987  
S D

DTIC FILE COPY

87 3

UNCLASSIFIED

SECURITY CLASSIFICATION OF THIS PAGE

ADA178167

## REPORT DOCUMENTATION PAGE

1a. REPORT SECURITY CLASSIFICATION Unclassified			1b. RESTRICTIVE MARKINGS		
2a. SECURITY CLASSIFICATION AUTHORITY			3. DISTRIBUTION/AVAILABILITY OF REPORT Approved for public release; distribution unlimited		
2b. DECLASSIFICATION/DOWNGRADING SCHEDULE					
4. PERFORMING ORGANIZATION REPORT NUMBER(S)  UBUFFALO/DC/87/TR-31			5. MONITORING ORGANIZATION REPORT NUMBER(S)		
6a. NAME OF PERFORMING ORGANIZATION Depts. Chemistry & Physics State University of New York		6b. OFFICE SYMBOL (If applicable)	7a. NAME OF MONITORING ORGANIZATION		
6c. ADDRESS (City, State and ZIP Code) Fronczak Hall, Amherst Campus Buffalo, New York 14260			7b. ADDRESS (City, State and ZIP Code) Chemistry Program 800 N. Quincy Street Arlington, Virginia 22217		
8a. NAME OF FUNDING/SPONSORING ORGANIZATION Office of Naval Research		8b. OFFICE SYMBOL (If applicable)	9. PROCUREMENT INSTRUMENT IDENTIFICATION NUMBER  Contract N00014-86-K-0043		
8c. ADDRESS (City, State and ZIP Code) Chemistry Program 800 N. Quincy Street Arlington, Virginia 22217			10. SOURCE OF FUNDING NOS.		
			PROGRAM ELEMENT NO.	PROJECT NO.	TASK NO.
			WORK UNIT NO.		
11. TITLE The Plasmon Dispersion Relation on a Rough Surface: A Simple Approximation					
12. PERSONAL AUTHOR(S) Daniel A. Jelski and Thomas F. George					
13a. TYPE OF REPORT		13b. TIME COVERED FROM _____ TO _____		14. DATE OF REPORT (Yr., Mo., Day) March 1987	
				15. PAGE COUNT 18	
16. SUPPLEMENTARY NOTATION Prepared for Publication in the Journal of Physical Chemistry					
17. COSATI CODES			18. SUBJECT TERMS (Continue on reverse if necessary and identify by block number)		
FIELD	GROUP	SUB. GR.	PLASMON DISPERSION RELATION, RAYLEIGH HYPOTHESIS; ROUGH SURFACE, P-POLARIZED LIGHT; CHEMICAL VAPOR DEPOSITION, COMPLEX DIELECTRIC CONSTANT		
19. ABSTRACT (Continue on reverse if necessary and identify by block number)  This paper is concerned with periodic, laser-induced, chemical vapor deposition recently observed experimentally. In order to inquire further into this phenomena, it is first necessary to find a simple means of calculating the plasmon field strength for relatively deep gratings. The Rayleigh hypothesis is assumed, and only p-polarized, normally incident light is considered. A closed-form equation for the plasmon field intensity is then derived. Also discussed is the behavior of the plasmon dispersion relation for a shallow grating, but for a complex dielectric constant where the imaginary part is not necessarily small.					
20. DISTRIBUTION/AVAILABILITY OF ABSTRACT UNCLASSIFIED/UNLIMITED <input checked="" type="checkbox"/> SAME AS RPT. <input checked="" type="checkbox"/> DTIC USERS <input type="checkbox"/>			21. ABSTRACT SECURITY CLASSIFICATION Unclassified		
22a. NAME OF RESPONSIBLE INDIVIDUAL Dr. David L. Nelson			22b. TELEPHONE NUMBER (Include Area Code) (202) 696-4410		22c. OFFICE SYMBOL

THE PLASMON DISPERSION RELATION ON A ROUGH SURFACE: A SIMPLE APPROXIMATION

Daniel A. Jelski and Thomas F. George

Departments of Chemistry and of Physics & Astronomy  
239 Fronczak Hall  
State University of New York at Buffalo  
Buffalo, New York 14260

ABSTRACT

This paper is concerned with periodic, laser-induced, chemical vapor deposition recently observed experimentally. In order to inquire further into this phenomena, it is first necessary to find a simple means of calculating the plasmon field strength for relatively deep gratings. The Rayleigh hypothesis is assumed, and only p-polarized, normally incident light is considered. A closed-form equation for the plasmon field intensity is then derived. Also discussed is the behavior of the plasmon dispersion relation for a shallow grating, but for a complex dielectric constant where the imaginary part is not necessarily small.

Accession For	
NTIS CRA&I	<input checked="checked" type="checkbox"/>
DTIC TAB	<input type="checkbox"/>
Unannounced	<input type="checkbox"/>
Justification	
By	
Distribution/	
Availability Codes	
Dist	Avail and/or Special
A-1	



## 1. Introduction

Our laboratory has been investigating laser-induced chemical vapor deposition processes as recently observed experimentally.<sup>1-3</sup> In particular, we have been interested in the periodic structures observed by Brueck and Ehrlich<sup>3</sup>. In a later paper, we shall discuss this experiment directly. This paper, however, will be devoted to developing the theoretical framework necessary for the calculations.

The periodic structure that is observed evolves from the plasmon field induced by the laser. The laser interacts with the random surface roughness. Because the plasmon is resonant at one frequency (for shallow gratings), that frequency component grows as

$$\frac{\partial \xi}{\partial t} = aI(x), \quad (1)$$

where  $\xi$  is the grating amplitude,  $I(x)$  is the total field intensity as a function of position, and  $a$  is the proportionality constant. From this it is clear that we need to develop expressions for the plasmon field intensity as a function of grating height and wavenumber. We can simplify the problem considerably in all that follows by assuming perpendicular incidence, in which case the  $x$ -dependence of the intensity depends only on the plasmon field and not on the reflected or incident fields. We can simplify the problem even further by using the Rayleigh expansion. This is an exact solution above the selvedge region and an approximation within the selvedge region. However, we are primarily interested in field strengths above the selvedge region, so that this expansion is justified.

Many authors have discussed the interaction of radiation with a rough surface or grating. Petit<sup>4</sup> has written a good introduction to the subject.

Maradudin<sup>5</sup> has discussed the behavior of surface polaritons and plasmons (which together are what we are generically referring to as a surface plasmon). In particular, he has worked out the theory for randomly rough surfaces and has written expressions for the dispersion relation using both the Rayleigh expansion and the exact formula using Green's functions. We shall make much use of this work as we go along. Other authors have also made significant contributions. Jha, Kirtley and Tsang<sup>6</sup> have developed the theory for a shallow grating. These authors have made extensive use of the work of Toigo, Marvin, Celli and Hill,<sup>7,8</sup> who have written the Rayleigh expansion in a remarkably simple form. Finally, Agassi and George<sup>9,10</sup> have developed a dressed Rayleigh expansion which eliminates many of the numerical difficulties encountered previously.

We are interested in the plasmon field intensity above the selvage region for reasonably deep gratings. We need an expression as a function of both grating height and grating wavenumber. Since we shall also need the derivatives of this function, it is important to derive an expression in closed form. To date, all calculations for deep gratings have involved the inversion of large matrices. Given the conditions of our application, this is impractical. Therefore, we must develop an approximation which is still valid in the deep grating case, but which provides a closed form equation for the plasmon field strength. Two recent papers<sup>11,12</sup> have made progress in this field. In particular, the work by Weber<sup>12</sup> represents a generalization of our present result. We will compare our result with his in the conclusion.

We should also point out that there has been considerable work done on a closely related problem. Fauchet and Siegman<sup>13</sup> have discovered ripples as a result of laser annealing, and Sipe et al.<sup>14</sup> have developed an elegant

theory to account for this phenomena. But these are effects of surface damage rather than surface deposition, and hence the theoretical requirements are more stringent in that the Rayleigh hypothesis can no longer be applied.

But there is one additional problem. The experiment of Brueck and Ehrlich involved a plasmon wave along a cadmium surface. The dielectric constant for cadmium (at UV frequencies) is approximately

$$\epsilon = -2.5 + 1.3i. \quad (2)$$

Most calculations, even for shallow gratings, have assumed that the imaginary part of the dielectric constant is either zero<sup>4,5</sup>, or small.<sup>6</sup> Since this is not the case for us, we shall digress a bit and discuss the effect on the dispersion relation as the imaginary part of the dielectric constant becomes large.

The remainder of this paper is organized as follows. In section 2 we shall discuss the dispersion relation as a function of dielectric constant. In section 3 we shall derive our approximate formula for the plasmon field strength. Section 4 contains a discussion of our results, including a numerical comparison of our approximation with the exact calculation.

## 2. Dispersion Relation

We can write the solution of the homogenous Helmholtz equation as

$$\underline{E}_a = E_1 \underline{p}_{\ell-} \exp(i[kx - \alpha_0 z]) + \sum_{\ell=-\infty}^{\infty} A_{\ell} \underline{p}_{\ell+} \exp(i[k_{\ell} x + \alpha_{\ell} z]) \quad (3)$$

$$z > \xi(x)$$



$$\underline{E}_b = \sqrt{\epsilon z} \int_l C_l \exp(i[k_l x - \beta_l z]) \quad (4)$$

$$z < \xi(x),$$

where

$$\begin{aligned} k &= \frac{\omega}{c} & \epsilon &= \epsilon_1 + i\epsilon_2 & \epsilon_1 &< -1 \\ k_l &= k_t + lk_g & \alpha_l &= (k^2 - k_l^2)^{1/2} & \text{Im}\alpha > 0 \\ & & & & \alpha_0 > 0 \end{aligned} \quad (5)$$

$$\beta_l = (\epsilon k^2 - k_l^2)^{1/2} \quad \text{Im}\beta_l > 0 \quad p_{l\pm} = \frac{1}{k}[k_l z \mp \alpha_l x]$$

and where  $k_g$  is the plasmon frequency and  $E_i$  the incident field strength. The notation has been culled from refs. 5 and 9. This solution is exact as long as one is outside the selvedge region. Within the selvedge region it may be a good approximation, but as mentioned previously, we are primarily concerned with the region outside, and hence we can use eqs. 4 and 5 without reservation. From the above, it is apparent that  $A_0$  is the reflected field, while  $A_l$  is the  $l$ -th order Bragg reflection ( $\alpha_l$  real), or surface plasmon ( $\alpha_l$  imaginary). We are interested in the plasmon effect, and hence we shall always assume that  $k_g > k$ .

Now, suppose that the surface profile is sinusoidal and can be written as

$$\xi(x) = \xi \cos(k_g x), \quad (6)$$

and that  $\xi$  is small. Then, for perpendicularly incident, p-polarized light, we can write the plasmon field strength as<sup>6</sup>

$$A_{\ell} = \frac{\alpha_0 \beta_{\ell} [k^2 \xi (\epsilon \alpha_{\ell} - \beta_{\ell})]}{\epsilon k^2 - k_g^2 (1 + \epsilon)} . \quad (7)$$

For small  $\xi$ ,  $A_{\ell}$  is very small unless the denominator is very small. If  $\epsilon$  is real, the denominator, which we shall call the resonance factor and denote by  $R$ , is zero if

$$k_g^2 = k^2 \frac{\epsilon_1}{\epsilon_1 + 1} . \quad (8)$$

This is the familiar plasmon resonance condition for a flat surface and a real dielectric constant. However, if  $\epsilon$  is complex then the strength of the plasmon field depends on the modulus of  $R$ , and it is no longer sufficient merely to minimize the real part. We must then minimize

$$|R|^2 = [k_g^2 (1 + \epsilon_1) - k^2 \epsilon_1]^2 + [\epsilon_2 (k_g^2 - k^2)]^2 . \quad (9)$$

Differentiating with respect to  $k_g$  and setting the result to zero, we obtain a new dispersion relation

$$k_g^2 = \frac{k^2 [\epsilon_1 (1 + \epsilon_1) - \epsilon_2^2]}{(1 + \epsilon_1)^2 + \epsilon_2^2} . \quad (10)$$

As  $\epsilon_2 \rightarrow 0$  this reduces to eq. 5. We also note that if  $\epsilon_2 \neq 0$ , then  $|R| \neq 0$ , and the resonance is both dampened and broadened. Equation 10 is the flat surface plasmon dispersion relation for an arbitrary, complex-valued dielectric constant.

As the grating becomes deeper,  $R$  also depends on higher powers of  $\xi_1$ , whereby a branching occurs in the dispersion relation and the resonance becomes less pronounced. Thus the mechanism of the periodic deposition process should now be clear. In the beginning, the incident light is resonant with one frequency component of the randomly rough, but very shallow grating. Because of this resonance, the plasmon of that frequency is much stronger than the others. Hence the field intensity is periodic, and deposition, following eq. 1, has the same periodicity, leading to a growth in amplitude of the grating.

As the grating becomes larger, the dispersion relation branches, and the resonance is correspondingly broadened and dampened. This results in a decrease in the periodicity of the field intensity and a corresponding decrease in the differential rate of deposition (i.e., deposition occurs evenly, not necessarily more slowly). Hence the grating stops growing.

### 3. Calculation of Plasmon Field Intensity

We can write an expression for the coefficients of eq. 3 as<sup>7,9</sup>

$$\sum_{l=-\infty}^{\infty} M_{m,l} A_l = \mu_m E_1, \quad (11)$$

where

$$M_{m,l} = \frac{\alpha_m \beta_l + k_l k_m}{\alpha_l + \beta_m} (i)^{m-l} J_{m-l}(\xi[\alpha_l - \beta_m]) \pi \quad (12)$$

$$\mu_m = \frac{-\alpha_0 \beta_m + k_0 k_m}{\alpha_0 + \beta_m} (i)^m J(\xi[\alpha_0 + \beta_m]), \quad (13)$$

and  $J_m(x)$  is the  $m$ -th-order Bessel function. In general, this results in an infinite number of coupled equations, from which the  $A_l$ 's can be extracted. In practice, Agassi and George<sup>9</sup> have shown that 50 equations is sufficient to find an accurate solution. However, in our circumstance this is impossible. We must find the plasmon field strength as a function of both grating height and wavenumber, which means that we would have to invert two  $50 \times 50$  real matrices for each data point. Using the approximation scheme which we shall derive, we have calculated 10,000 data points. This is perhaps more than necessary, but doing so has enabled us to thoroughly understand the behavior of these functions.

For our approximation, we borrow a page from Maradudin<sup>5</sup> and extend that result to higher orders. The method rests on two ideas. One is that if  $A_1$  is a plasmon at resonance with  $k_g$ , then

$$A_1 \gg A_m \quad m \neq 1. \quad (14)$$

The second condition is to note that

$$M_{nn} \sim 1, \quad M_{n,n\pm 1} \sim \xi, \quad M_{n,n\pm 2} \sim \xi^2, \dots \quad (15)$$

so that even for reasonably deep gratings we can assume that  $M_{11} > M_{12} > M_{13}$  etc.

A special case of eq. 11 is

$$M_{11}A_1 + \sum_{m \neq 1} M_{1,m}A_m = \mu_1 E_i \quad (16)$$

or

$$A_1 = \frac{\mu_1 E_i + \sum_{m \neq 1} M_{1,m}A_m}{M_{11}}. \quad (17)$$

Thus  $R = M_{11}$ , which must therefore go to zero if  $A_1$  is to be resonant.

Expanding  $A_{11}$  to first order in  $\xi$  yields our result of eq. 4.

Equation 17 is exact. Now we make our approximation. Suppose that  $m \neq 1$ . Then we can write

$$M_{mm}A_m + \sum_{p \neq m} M_{mp}A_p = \mu_m E_i \quad (18)$$

But because we are at resonance, of the sum over  $p$ ,  $p=1$  is by far the largest term. Thus we can simplify eq. 18 as

$$A_m = \frac{\mu_m E_i - M_{m,1}A_1}{M_{mm}}. \quad (19)$$

Substituting eq. 19 into 17, we obtain

$$A_1 = \frac{(\mu_1 - \sum_{p \neq 1} \frac{M_{1p}}{M_{pp}} \mu_p) E_i}{M_{11} - \sum_{p \neq 1} \frac{M_{1p} M_{p1}}{M_{pp}}}. \quad (20)$$

In the case of normal incidence,  $A_1 = A_{-1}$  by symmetry, and we are not justified in leaving  $A_{-1}$  out of eq. 19. Inclusion of this term for normal incidence yields

$$A_1 = \frac{(\mu_1 - \sum_{p \neq 1} (M_{1p} + M_{1-p}) \frac{\mu_p}{M_{pp}}) E_1}{[(M_{11} + M_{1-1}) - \sum_{p \neq 1} (M_{1p} + M_{1-p})(M_{p1} + M_{p-1}) \frac{1}{M_{pp}}]} \quad (21)$$

where  $p$  is summed only over non-negative integers. It is clear that in the shallow grating case, both eqs. 20 and 21 reduce to eq. 7.

We shall use eq. 21 with one modification: To ensure numerical convergence, we shall use the dressed Rayleigh expansion.<sup>9</sup> Thus we rewrite eq. 10 as

$$\sum_{l=-\infty}^{\infty} M_{m,l}^D A_l^D = \mu_m^D E_1 \quad (22)$$

where

$$M_{m,n}^D = M_{m,n} \exp(i\xi[\alpha_n + \beta_m]) \quad (23)$$

$$\mu_m^D = \mu_m \exp(i\beta_m \xi), \quad A_n^D = A_n \exp(i\alpha_n \xi).$$

This eliminates numerical instabilities, not only in the exact calculation, but also for our approximation. In practice, for the grating heights of interest, we have found that summing  $p$  from 0 to 15 in eq. 21 provides sufficient accuracy.

#### 4. Conclusion

Equation 21, modified if necessary by the transformation of eq. 23, constitutes our closed form approximation for the plasmon field strength. Let us consider the advantages and shortcomings of our approximation. The first constraint is to notice that for our approximation to be valid, eq. 14 must hold. This means that we must be on the resonance frequency. Were we not on the resonance frequency, then the approximation used in deriving eq. 19 would not be valid. Secondly, our approximation still is a function of grating height. Note that we have used eq. 15, which means that we are discarding higher orders of  $\xi$  for non-resonant plasmons. As these become large, then our approximation becomes less accurate.

Nevertheless, we are happy to report that this method preserves the qualitative features of the full calculation. Figure 1 illustrates this very clearly. Here we have calculated the plasmon field strength ( $|A_1|$ ) for various grating heights using both our new method and the full calculation. It is clear that for gratings up to  $\xi \approx 25$  nm, the simple calculation preserves the qualitative features of the exact method. This corresponds to a value of  $k_g \xi \approx .7$ , which is a very deep grating. The quantitative picture may also be better than appears in the graph. The calculation was done for  $k_g = 2.95 \times 10^7 \text{ m}^{-1}$ . This is the resonance frequency for shallow gratings, but it is off resonance for deeper gratings. At 25 nm, we have observed that the resonance frequency is closer to  $3.1 \times 10^7 \text{ m}^{-1}$ . We have ignored this shift in frequency in our calculations.

As mentioned previously, our result compares with the more general result of Weber.<sup>12</sup> His is more general in that it explicitly accounts for three terms in the Rayleigh expansion rather than just one. However, at resonance, the other two terms can be expected to contribute negligibly, and



hence our result should be nearly as accurate. Off resonance, of course, the other terms are significant and Weber's method is clearly preferable. Strict numerical comparison is impossible since he did his calculation using silver, with a small  $\epsilon_2$ , whereas ours is for cadmium. Furthermore, his example is for a sawtooth grating while ours is for a sinusoidal grating. But it is very clear from a comparison of figure 1 with his table I that the same qualitative features hold, namely that the plasmon resonance intensity is underestimated. Our formalism, while not as general, is derived much more simply and is easier to use, and is probably just as accurate where applicable.

In a later paper<sup>15</sup> we shall apply this formalism to the problem of periodic, laser-induced, chemical vapor deposition. We should be able to predict the growth rate and maximum peak height using the above method.

Acknowledgements

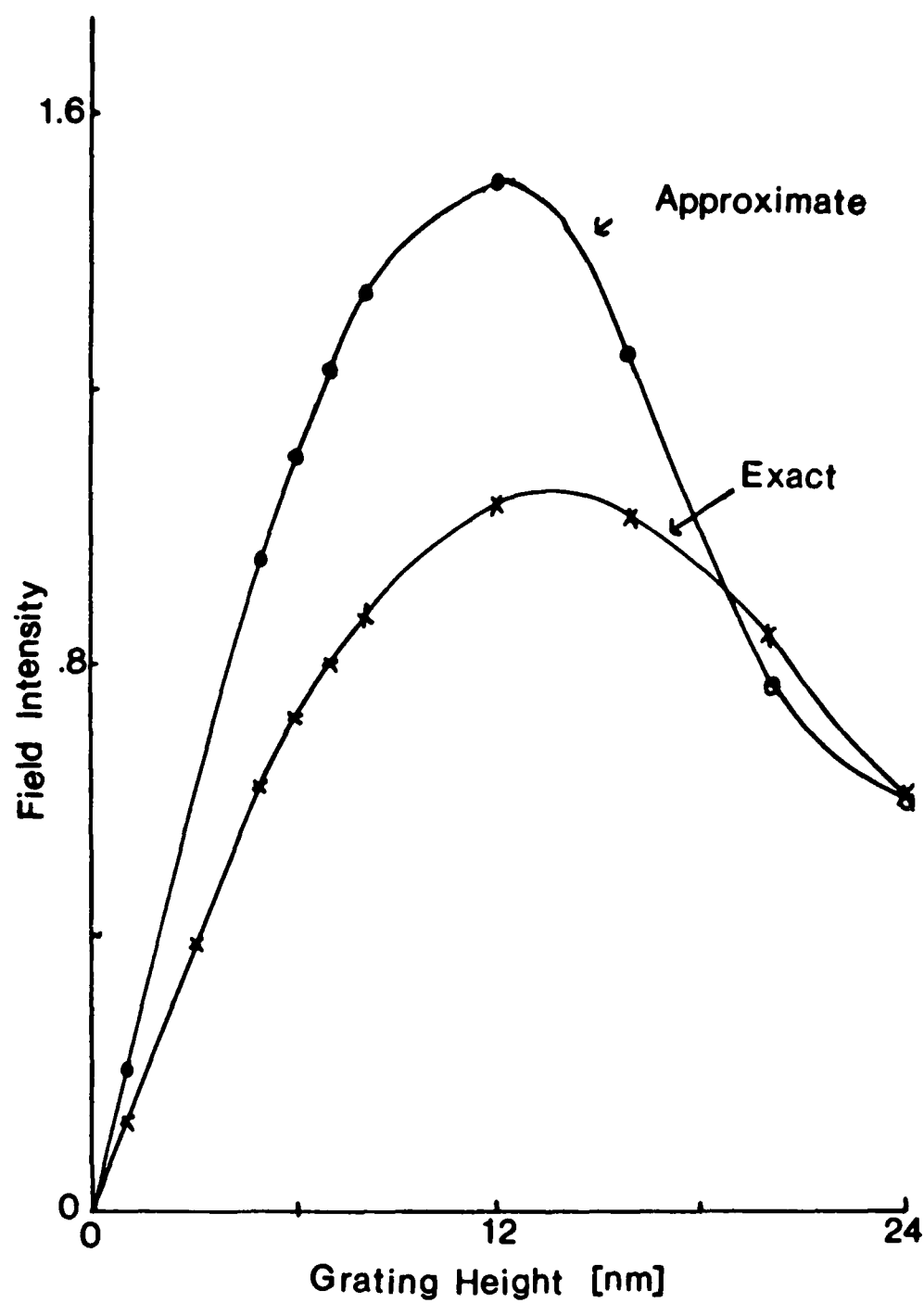
D. A. J. gratefully acknowledges the invaluable assistance of Dr. Pu<sup>1</sup>-Tak Leung and also appreciates the help of other members of our research group. We would like to thank a referee for bringing refs. 11 and 12 to our attention. This research was supported by the Office of Naval Research and the Air Force Office of Scientific Research (AFSC), United States Air Force, under Contract F49620-86-C-0009. The United States Government is authorized to reproduce and distribute reprints notwithstanding any copyright notation hereon.

## References

1. D.J. Ehrlich and J.Y. Tsao, J. Vac. Sci. Technol. B 1, 4, 969 (1983), and references therein.
2. R.M. Osgood, Jr., and D.J. Ehrlich, Opt. Lett. 7, 385 (1982).
3. S.R.J. Brueck and D.J. Ehrlich, Phys. Rev. Lett. 48, 1678 (1982).
4. R. Petit, in Electromagnetic Theory of Gratings, edited by R. Petit (Springer-Verlag, Berlin, 1980), Chapt. 1.
5. A.A. Maradudin, in Surface Polaritons, edited by V.M. Agranovich and D.L. Mills (North-Holland, Amsterdam, 1982), Chapt. 10.
6. S.S. Jha, J.R. Kirtley and J.C. Tsang, Phys. Rev. B 22, 3973 (1980).
7. F. Toigo, A. Marvin, V. Celli and N.R. Hill, Phys. Rev. B 15, 5618 (1977).
8. A. Marvin, F. Toigo and V. Celli, Phys. Rev. B 11, 2777 (1975).
9. D. Agassi and T.F. George, Phys. Rev. B 33, 2393 (1986).
10. D. Agassi and T.F. George, Surf. Sci. 172, 230 (1986).
11. N.E. Glass, M. Weber and D.L. Mills, Phys. Rev. B 29, 6548 (1984).
12. M.G. Weber, Phys. Rev. B 33, 9, (1986).
13. P.M. Fauchet and A.E. Siegman, Appl. Phys. Lett. 40, 824 (1982).
14. J.E. Sipe, J.F. Young, J.S. Preston and H.M. van Driel, Phys. Rev. B 27, 1141 (1983).
15. D.A. Jelski and T.F. George, J. Appl. Phys., in press.

## FIGURE CAPTION

Figure 1. This graph compares the plasmon field strength ( $|A_1|$ ) calculated from eq. 21 (using the dressed Rayleigh expansion) with that from the exact method. The dielectric constant used is  $-2.5 + 1.3i$ , the incident light has a wavelength of 257 nm ( $k = 2.44 \times 10^7 \text{ m}^{-1}$ ), and the grating wavenumber is taken as  $2.95 \times 10^7 \text{ m}^{-1}$ .



TECHNICAL REPORT DISTRIBUTION LIST, GEN

	<u>No. Copies</u>		<u>No. Copies</u>
Office of Naval Research Attn: Code 1113 800 N. Quincy Street Arlington, Virginia 22217-5000	2	Dr. David Young Code 334 NORDA NSTL, Mississippi 39529	1
Dr. Bernard Douda Naval Weapons Support Center Code 50C Crane, Indiana 47522-5050	1	Naval Weapons Center Attn: Dr. Ron Atkins Chemistry Division China Lake, California 93555	1
Naval Civil Engineering Laboratory Attn: Dr. R. W. Drisko, Code L52 Port Hueneme, California 93401	1	Scientific Advisor Commandant of the Marine Corps Code RD-1 Washington, D.C. 20380	1
Defense Technical Information Center Building 5, Cameron Station Alexandria, Virginia 22314	12 high quality	U.S. Army Research Office Attn: CRD-AA-IP P.O. Box 12211 Research Triangle Park, NC 27709	1
DTNSRDC Attn: Dr. H. Singerman Applied Chemistry Division Annapolis, Maryland 21401	1	Mr. John Boyle Materials Branch Naval Ship Engineering Center Philadelphia, Pennsylvania 19112	1
Dr. William Tolles Superintendent Chemistry Division, Code 6100 Naval Research Laboratory Washington, D.C. 20375-5000	1	Naval Ocean Systems Center Attn: Dr. S. Yamamoto Marine Sciences Division San Diego, California 91232	1
		Dr. David L. Nelson Chemistry Division Office of Naval Research 800 North Quincy Street Arlington, Virginia 22217	1

ABSTRACTS DISTRIBUTION LIST, 056/625/629

Dr. J. E. Jensen  
Hughes Research Laboratory  
3011 Malibu Canyon Road  
Malibu, California 90265

Dr. J. H. Weaver  
Department of Chemical Engineering  
and Materials Science  
University of Minnesota  
Minneapolis, Minnesota 55455

Dr. A. Reisman  
Microelectronics Center of North Carolina  
Research Triangle Park, North Carolina  
27709

Dr. M. Grunze  
Laboratory for Surface Science and  
Technology  
University of Maine  
Orono, Maine 04469

Dr. J. Butler  
Naval Research Laboratory  
Code 6115  
Washington D.C. 20375-5000

Dr. L. Interante  
Chemistry Department  
Rensselaer Polytechnic Institute  
Troy, New York 12181

Dr. Irvin Heard  
Chemistry and Physics Department  
Lincoln University  
Lincoln University, Pennsylvania 19352

Dr. K.J. Klaubunde  
Department of Chemistry  
Kansas State University  
Manhattan, Kansas 66506

Dr. C. B. Harris  
Department of Chemistry  
University of California  
Berkeley, California 94720

Dr. F. Kutzler  
Department of Chemistry  
Box 5055  
Tennessee Technological University  
Cookeville, Tennessee 38501

Dr. D. DiLella  
Chemistry Department  
George Washington University  
Washington D.C. 20052

Dr. R. Reeves  
Chemistry Department  
Rensselaer Polytechnic Institute  
Troy, New York 12181

Dr. Steven M. George  
Stanford University  
Department of Chemistry  
Stanford, CA 94305

Dr. Mark Johnson  
Yale University  
Department of Chemistry  
New Haven, CT 06511-8118

Dr. W. Knauer  
Hughes Research Laboratory  
3011 Malibu Canyon Road  
Malibu, California 90265

ABSTRACTS DISTRIBUTION LIST, 056/625/629

Dr. G. A. Somorjai  
Department of Chemistry  
University of California  
Berkeley, California 94720

Dr. J. Murday  
Naval Research Laboratory  
Code 6170  
Washington, D.C. 20375-5000

Dr. J. B. Hudson  
Materials Division  
Rensselaer Polytechnic Institute  
Troy, New York 12181

Dr. Theodore E. Madey  
Surface Chemistry Section  
Department of Commerce  
National Bureau of Standards  
Washington, D.C. 20234

Dr. J. E. Demuth  
IBM Corporation  
Thomas J. Watson Research Center  
P.O. Box 218  
Yorktown Heights, New York 10598

Dr. M. G. Lagally  
Department of Metallurgical  
and Mining Engineering  
University of Wisconsin  
Madison, Wisconsin 53706

Dr. R. P. Van Duyne  
Chemistry Department  
Northwestern University  
Evanston, Illinois 60637

Dr. J. M. White  
Department of Chemistry  
University of Texas  
Austin, Texas 78712

Dr. D. E. Harrison  
Department of Physics  
Naval Postgraduate School  
Monterey, California 93940

Dr. R. L. Park  
Director, Center of Materials  
Research  
University of Maryland  
College Park, Maryland 20742

Dr. W. T. Peria  
Electrical Engineering Department  
University of Minnesota  
Minneapolis, Minnesota 55455

Dr. Keith H. Johnson  
Department of Metallurgy and  
Materials Science  
Massachusetts Institute of Technology  
Cambridge, Massachusetts 02139

Dr. S. Sibener  
Department of Chemistry  
James Franck Institute  
5640 Ellis Avenue  
Chicago, Illinois 60637

Dr. Arnold Green  
Quantum Surface Dynamics Branch  
Code 3817  
Naval Weapons Center  
China Lake, California 93555

Dr. A. Wold  
Department of Chemistry  
Brown University  
Providence, Rhode Island 02912

Dr. S. L. Bernasek  
Department of Chemistry  
Princeton University  
Princeton, New Jersey 08544

Dr. W. Kohn  
Department of Physics  
University of California, San Diego  
La Jolla, California 92037



ABSTRACTS DISTRIBUTION LIST, 056/625/629

Dr. F. Carter  
Code 6170  
Naval Research Laboratory  
Washington, D.C. 20375-5000

Dr. Richard Colton  
Code 6170  
Naval Research Laboratory  
Washington, D.C. 20375-5000

Dr. Dan Pierce  
National Bureau of Standards  
Optical Physics Division  
Washington, D.C. 20234

Dr. R. Stanley Williams  
Department of Chemistry  
University of California  
Los Angeles, California 90024

Dr. R. P. Messmer  
Materials Characterization Lab.  
General Electric Company  
Schenectady, New York 22217

Dr. Robert Gomer  
Department of Chemistry  
James Franck Institute  
5640 Ellis Avenue  
Chicago, Illinois 60637

Dr. Ronald Lee  
R301  
Naval Surface Weapons Center  
White Oak  
Silver Spring, Maryland 20910

Dr. Paul Schoen  
Code 6190  
Naval Research Laboratory  
Washington, D.C. 20375-5000

Dr. John T. Yates  
Department of Chemistry  
University of Pittsburgh  
Pittsburgh, Pennsylvania 15260

Dr. Richard Greene  
Code 5230  
Naval Research Laboratory  
Washington, D.C. 20375-5000

Dr. L. Kesmodel  
Department of Physics  
Indiana University  
Bloomington, Indiana 47403

Dr. K. C. Janda  
University of Pittsburgh  
Chemistry Building  
Pittsburg, PA 15260

Dr. E. A. Irene  
Department of Chemistry  
University of North Carolina  
Chapel Hill, North Carolina 27514

Dr. Adam Heller  
Bell Laboratories  
Murray Hill, New Jersey 07974

Dr. Martin Fleischmann  
Department of Chemistry  
University of Southampton  
Southampton SO9 5NH  
UNITED KINGDOM

Dr. H. Tachikawa  
Chemistry Department  
Jackson State University  
Jackson, Mississippi 39217

Dr. John W. Wilkins  
Cornell University  
Laboratory of Atomic and  
Solid State Physics  
Ithaca, New York 14853

ABSTRACTS DISTRIBUTION LIST, 056/625/629

Dr. R. G. Wallis  
Department of Physics  
University of California  
Irvine, California 92664

Dr. D. Ramaker  
Chemistry Department  
George Washington University  
Washington, D.C. 20052

Dr. J. C. Hemminger  
Chemistry Department  
University of California  
Irvine, California 92717

Dr. T. F. George  
Chemistry Department  
University of Rochester  
Rochester, New York 14627

Dr. G. Rubloff  
IBM  
Thomas J. Watson Research Center  
P.O. Box 218  
Yorktown Heights, New York 10598

Dr. Horia Metiu  
Chemistry Department  
University of California  
Santa Barbara, California 93106

Dr. W. Goddard  
Department of Chemistry and Chemical  
Engineering  
California Institute of Technology  
Pasadena, California 91125

Dr. P. Hansma  
Department of Physics  
University of California  
Santa Barbara, California 93106

Dr. J. Baldeschwieler  
Department of Chemistry and  
Chemical Engineering  
California Institute of Technology  
Pasadena, California 91125

Dr. J. T. Keiser  
Department of Chemistry  
University of Richmond  
Richmond, Virginia 23173

Dr. R. W. Plummer  
Department of Physics  
University of Pennsylvania  
Philadelphia, Pennsylvania 19104

Dr. E. Yeager  
Department of Chemistry  
Case Western Reserve University  
Cleveland, Ohio 41105

Dr. N. Winograd  
Department of Chemistry  
Pennsylvania State University  
University Park, Pennsylvania 16802

Dr. Roald Hoffmann  
Department of Chemistry  
Cornell University  
Ithaca, New York 14853

Dr. A. Steckl  
Department of Electrical and  
Systems Engineering  
Rensselaer Polytechnic Institute  
Troy, New York 12181

Dr. G.H. Morrison  
Department of Chemistry  
Cornell University  
Ithaca, New York 14853

END

4-87

DTIC